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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/617,826	CHEN ET AL.	
Examiner	Art Unit	
Leon J. Harper	2166	

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Class	Subclass	Date	Examiner	
707	104.1, 200, 100 1, 4,10	1/4/2005	LJH	
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
consulted with K. pham about prior art	1/5/2005	LJH